



Single Crystal Diamond Tips+Silicon Cantilevers-300

SCDT-SC-300

The Single Crystal Diamond (SCD) probes have tips specially grown in a CVD process and glued to silicon cantilevers for use in AFM. These durable and chemically inert probes with high aspect ratio and small tip radius are now offered at an affordable price comparable to that of traditional silicon probes. SCD tips usually have a sharp edge at the apex which makes it applicable for imaging flat surfaces with high resolution. The typical SCD tip radius is less than that of a silicon AFM tip, which makes it applicable for general purpose AFM imaging. The advantage of SCD is that the tip is extremely robust in any scanning mode and cleanable from contaminants.

SPECIFICATIONS

short_desc	Single Crystal Diamond Tips on Silicon Cantilevers
Categories	AFM Probes, Diamond
Tags	: Atomic Force Acoustic Microscopy (AFAM), General Topography, Hardened/Enhanced Wear Resistance, Life Sciences, Mechanical Properties/Force Curves, Nanoindentation and Lithography, Non-Contact/Tapping, Phase Imaging Mode
Quantity	5
Cantilever Length	125
Cantilever Width	35
Cantilever Thickness	4
Resonant Frequency [kHz]	265, 300, 400
Force Constant [N/m]	20, 40, 75
Coating	Al Reflective
Cantilever Shape	Rectangular
Cantilever	Single
Tip Material	Single Crystal Diamond (SCD)

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